

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Philippe TAILHADES et al.

Application No.: 10/582,520

Filed: June 9, 2006

Docket No.: 128360

For: THE USE OF SPINEL FERRITES AS SENSITIVE MATERIAL FOR BOLOMETRIC

INFRARED DETECTOR DEVICES

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- This Information Disclosure Statement is being filed (a) within three months of
 the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first
 Office Action on the merits in the present application. No certification or fee is required.
- Relevance of one or more non-English language reference is discussed in the present specification. See Reference 2.
- 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 1 and 2.

4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.

Respectfully submitted,

William P. Berridge Registration No. 30,024

Julie M. Lake Registration No. 51,156

WPB:JML/emt

Date: August 28, 2006

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461 AUG 2 8 2006

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